Power MOSFET

30 V, 52 A, Single N-Channel, μ8FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Low-Side DC-DC Converters
- Power Load Switch
- Notebook Battery Management
- Motor Control

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

| Param | Symbol | Value | Unit | | |
|---|--------------------------------------|---------------------------|----------------------|------|---|
| Drain-to-Source Voltage | V_{DSS} | 30 | V | | |
| Gate-to-Source Voltage | V_{GS} | ±20 | V | | |
| Continuous Drain | | T _A = 25°C | I _D | 14.3 | Α |
| Current R _{θJA} (Note 1) | | T _A = 85°C | | 10.3 | |
| Power Dissipation $R_{\theta JA}$ (Note 1) | | T _A = 25°C | P _D | 2.21 | W |
| Continuous Drain | | T _A = 25°C | I _D | 20.3 | Α |
| Current R _{θJA} ≤ 10 s (Note 1) | | T _A = 85°C | | 14.7 | |
| Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$ | Steady | T _A = 25°C | P _D | 4.48 | W |
| Continuous Drain | State | T _A = 25°C | I _D | 8.9 | Α |
| Current R _{θJA} (Note 2) | | T _A = 85°C | | 6.4 | |
| Power Dissipation $R_{\theta JA}$ (Note 2) | | T _A = 25°C | P _D | 0.85 | W |
| Continuous Drain | | T _C = 25°C | I _D | 52 | Α |
| Current R _{θJC} (Note 1) | | T _C = 85°C | | 38 | |
| Power Dissipation $R_{\theta JC}$ (Note 1) | | T _C = 25°C | P _D | 29.8 | W |
| Pulsed Drain Current | T _A = 25°0 | C, t _p = 10 μs | I_{DM} | 170 | Α |
| Current Limited by Pkg. | T _A | = 25°C | I _{DmaxPkg} | 70 | Α |
| Operating Junction and S | T _J , T _{stg} | -55 to +150 | °C | | |
| Source Current (Body Die | I _S | 35 | Α | | |
| Drain to Source DV/DT | dV/dt | 6.0 | V/ns | | |
| Single Pulse Drain-to-So $(T_J = 25^{\circ}C, V_{DD} = 50 \text{ V}, \text{V}_{L} = 31 \text{ A}_{pk}, L = 0.1 \text{ mH}, F$ | E _{AS} | 48 | mJ | | |
| Lead Temperature for So (1/8" from case for 10 s) | TL | 260 | °C | | |

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

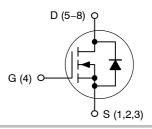


ON Semiconductor®

http://onsemi.com

| V _{(BR)DSS} R _{DS(on)} MAX | | I _D MAX |
|--|----------------|--------------------|
| 30 V | 5.5 mΩ @ 10 V | 52 A |
| | 8.0 mΩ @ 4.5 V | 32 A |

N-Channel MOSFET





WDFN8 (μ8FL) CASE 511AB



4939 = Specific Device Code
A = Assembly Location
Y = Year

www = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

| Device | Package | Shipping [†] |
|---------------|--------------------|-----------------------|
| NTTFS4939NTAG | WDFN8 (Pb-Free) | 1500/Tape & Reel |
| NTTFS4939NTWG | WDFN8 (Pb-Free) | 5000/Tape & Reel |

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

| Parameter | Symbol | Value | Unit |
|--|-----------------|-------|------|
| Junction-to-Case (Drain) | $R_{	heta JC}$ | 4.2 | °C/W |
| Junction-to-Ambient - Steady State (Note 3) | $R_{	heta JA}$ | 56.5 | |
| Junction-to-Ambient - Steady State (Note 4) | $R_{	heta JA}$ | 146.5 | |
| Junction-to-Ambient – (t \leq 10 s) (Note 3) | $R_{\theta JA}$ | 28 | |

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise specified)

| Parameter | Symbol | Test Condition | | Min | Тур | Max | Unit |
|--|--------------------------------------|---|--|-----|------|------|-------|
| OFF CHARACTERISTICS | • | | - | | - | - | • |
| Drain-to-Source Breakdown Voltage | V _{(BR)DSS} | V _{GS} = 0 V, I _D = 250 μA | | 30 | | | V |
| Drain-to-Source Breakdown Voltage Temperature Coefficient | V _{(BR)DSS} /T _J | | | | 15 | | mV/°C |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{GS} = 0 V, V _{DS} = 24 V | $T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$ | | | 1.0 | μΑ |
| Gate-to-Source Leakage Current | I _{GSS} | V _{DS} = 0 V, V _{GS} | s = ±20 V | | | ±100 | nA |
| ON CHARACTERISTICS (Note 5) | l | | | | ı | | 1 |
| Gate Threshold Voltage | V _{GS(TH)} | $V_{GS} = V_{DS}, I_D$ | = 250 μΑ | 1.2 | | 2.2 | V |
| Negative Threshold Temperature Coefficient | V _{GS(TH)} /T _J | | | | 4.0 | | mV/°C |
| Drain-to-Source On Resistance | $R_{DS(on)}$ $V_{GS} = 10 \text{ V}$ | \/ | I _D = 20 A | | 4.1 | 5.5 | mΩ |
| | | V _{GS} = 10 V | I _D = 10 A | | 4.1 | | 1 |
| | \/ A.F.\/ | I _D = 20 A | | 6.0 | 8.0 | 1 | |
| | | $V_{GS} = 4.5 V$ | I _D = 10 A | | 5.9 | | |
| Forward Transconductance | g _{FS} | V _{DS} = 1.5 V, I _D = 15 A | | | 35 | | S |
| CHARGES AND CAPACITANCES | | | | | | | |
| Input Capacitance | C _{iss} | V _{GS} = 0 V, f = 1.0 MHz, V _{DS} = 15 V | | | 1979 | | pF |
| Output Capacitance | C _{oss} | | | | 711 | | |
| Reverse Transfer Capacitance | C _{rss} | | | | 20.2 | | |
| Total Gate Charge | Q _{G(TOT)} | | | | 12.4 | | nC |
| Threshold Gate Charge | Q _{G(TH)} | V _{GS} = 4.5 V, V _{DS} = 1 | IE V I 00 A | | 3.2 | | |
| Gate-to-Source Charge | Q_{GS} | $v_{GS} = 4.5 \text{ v}, v_{DS} = 1$ | 15 V, ID = 20 A | | 6.0 | | |
| Gate-to-Drain Charge | Q_{GD} | 1 | | | 1.8 | | |
| Total Gate Charge | Q _{G(TOT)} | V _{GS} = 10 V, V _{DS} = 15 V, I _D = 20 A | | | 28 | | nC |
| SWITCHING CHARACTERISTICS (N | ote 6) | | | | | | |
| Turn-On Delay Time | t _{d(on)} | V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω | | | 12.2 | | ns |
| Rise Time | t _r | | | | 20.6 | | |
| Turn-Off Delay Time | t _{d(off)} | | | | 20.8 | | |
| Fall Time | t _f | | | | 3.9 | | |

^{5.} Pulse Test: pulse width = 300 μ s, duty cycle \leq 2%.

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size (40 mm², 1 oz. Cu).

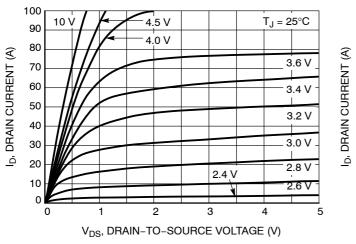
^{6.} Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

| | , - | · | * | | | | |
|---------------------------|---------------------|---|------------------------|-----|-------|-----|------|
| Parameter | Symbol | Test Condition | | Min | Тур | Max | Unit |
| SWITCHING CHARACTERISTICS | S (Note 6) | | | | | | |
| Turn-On Delay Time | t _{d(on)} | | | | 8.7 | | ns |
| Rise Time | t _r | V _{GS} = 10 V, V _{DS} | = 15 V, | | 19.5 | | 1 |
| Turn-Off Delay Time | t _{d(off)} | $I_D = 15 \text{ A}, R_G =$ | | | 25.3 | | 1 |
| Fall Time | t _f | 1 | | | 3.2 | | 1 |
| DRAIN-SOURCE DIODE CHARA | CTERISTICS | | • | | | | |
| Forward Diode Voltage | V _{SD} | VGS - 0 V, | $T_J = 25^{\circ}C$ | | 0.84 | 1.2 | V |
| | | | T _J = 125°C | | 0.71 | | 1 |
| Reverse Recovery Time | t _{RR} | $V_{GS} = 0 \text{ V, } d_{IS}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 20 \text{ A}$ | | | 35.5 | | ns |
| Charge Time | ta | | | | 19 | | 1 |
| Discharge Time | t _b | | | | 16.5 | | 1 |
| Reverse Recovery Charge | Q _{RR} | | | | 28 | | nC |
| PACKAGE PARASITIC VALUES | | | | | | | |
| Source Inductance | L _S | | | | 0.38 | | nΗ |
| Drain Inductance | L _D | T _A = 25°C | | | 0.054 | | 1 |
| Gate Inductance | L _G | | | | 1.3 | | 1 |
| Gate Resistance | R_{G} | | | | 1.1 | 2.0 | Ω |

^{5.} Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

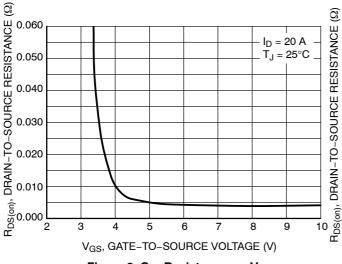
TYPICAL CHARACTERISTICS



75 $V_{DS} \ge 10 \text{ V}$ 70 65 60 55 50 45 40 35 30 $T_J = 25^{\circ}C$ 25 20 15 10 $T_J = -55^{\circ}C$ 0 1.0 2.0 2.5 3.0 3.5 4.0 V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



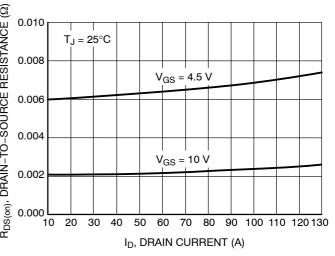
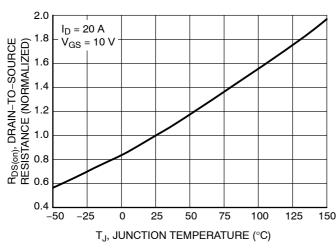


Figure 3. On-Resistance vs. V_{GS}

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



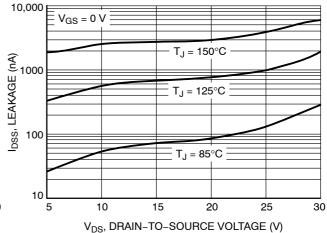


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

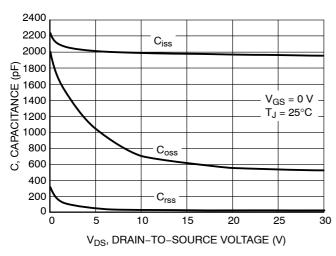


Figure 7. Capacitance Variation

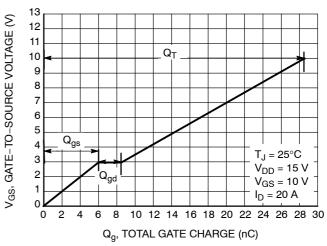


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

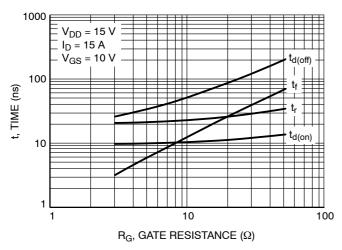


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

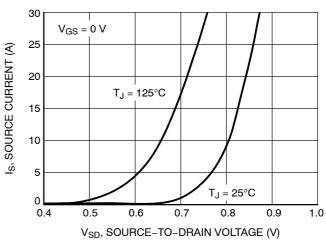


Figure 10. Diode Forward Voltage vs. Current

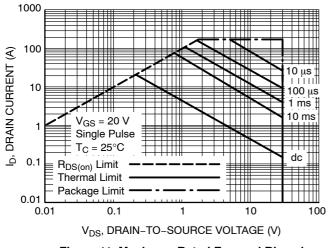


Figure 11. Maximum Rated Forward Biased Safe Operating Area

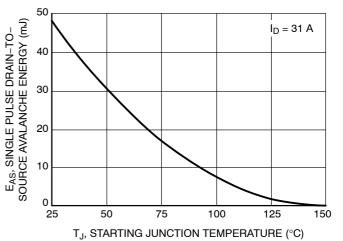


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

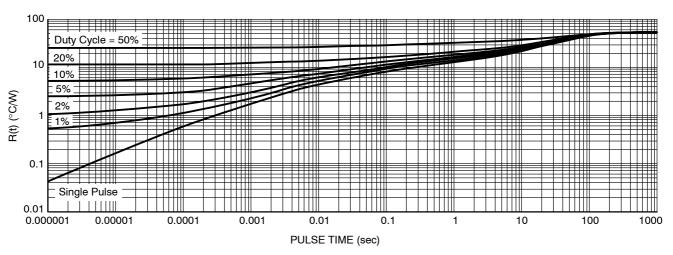
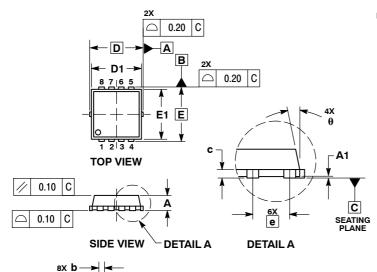


Figure 13. Thermal Response

PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65P CASE 511AB-01 **ISSUE B**

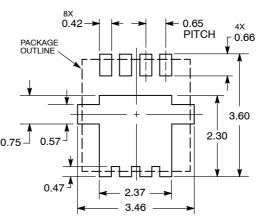


NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

| | MILLIMETERS | | | INCHES | | | |
|-----|-------------|----------|------|-----------|----------|-------|--|
| DIM | MIN | NOM | MAX | MIN | NOM | MAX | |
| Α | 0.70 | 0.75 | 0.80 | 0.028 | 0.030 | 0.031 | |
| A1 | 0.00 | | 0.05 | 0.000 | | 0.002 | |
| b | 0.23 | 0.30 | 0.40 | 0.009 | 0.012 | 0.016 | |
| С | 0.15 | 0.20 | 0.25 | 0.006 | 0.008 | 0.010 | |
| D | | 3.30 BSC | | C | .130 BSC |) | |
| D1 | 2.95 | 3.05 | 3.15 | 0.116 | 0.120 | 0.124 | |
| D2 | 1.98 | 2.11 | 2.24 | 0.078 | 0.083 | 0.088 | |
| E | | 3.30 BSC | | 0.130 BSC | | | |
| E1 | 2.95 | 3.05 | 3.15 | 0.116 | 0.120 | 0.124 | |
| E2 | 1.47 | 1.60 | 1.73 | 0.058 | 0.063 | 0.068 | |
| е | | 0.65 BSC | ; | 0.026 BSC | | | |
| G | 0.30 | 0.41 | 0.51 | 0.012 | 0.016 | 0.020 | |
| K | 0.64 | | | 0.025 | | | |
| L | 0.30 | 0.43 | 0.56 | 0.012 | 0.017 | 0.022 | |
| L1 | 0.06 | 0.13 | 0.20 | 0.002 | 0.005 | 0.008 | |
| М | 1.40 | 1.50 | 1.60 | 0.055 | 0.059 | 0.063 | |
| θ | 0 ° | | 12 ° | 0 ° | | 12 ° | |

SOLDERING FOOTPRINT*



DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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